



Contact resistivity measurement and simulation of current sharing around dropouts in CORC cables

Summary of FES SBIR Phase 1 with ACT

Jeremy Weiss (PI) and Danko van der Laan - *Advanced Conductor Technologies*
Reed Teyber (Subaward)- *LBNL*

Background and Outline



Advanced Conductor Technologies LLC
www.advancedconductor.com

- Phase 1 SBIR via DOE FES to develop long-length CORC cables (ACT -> LBNL)
 - Large coils will need cables longer than tape lengths
 - R&D is relevant to developing lower-cost HTS cables using lower-quality tapes
 - **See Lance Cooley / Jeremy Weiss et al previous VIC cable program for motivation**
 - Ongoing FES phase2B on Hall-based Quench Detection producing results, but not discussed today
- Outline for today
 - Difficulties scaling CORC network model
 - Contact resistivity extraction in Tapes (see Virginia Phifer + Lance Cooley's paper)
 - Potential as future modeling tool for CORC cables with low / variable performance tapes

No MDP resources being used for these, but making progress

*AllId- Develop quality control capabilities to identify defects and performance limiting regions
M13 in REBCO cables and accelerator magnets*

*In R.
progress Nov-23 Teyber*

*AllId- Advance numerical and experimental abilities to monitor and predict current
M14 distributions in ReBCO cables for accelerator magnets*

*In R.
progress Mar-24 Teyber*

Challenges with Network modeling

- LBNL Goal: use published CORC network model to inform cable design
 - First focus on contact resistivity extraction
 - Scale model to fit ACT measurements on cable with / without dropouts
 - Scaling model to more tapes + longer lengths proved problematic!
 - Needs future development towards high performance computing

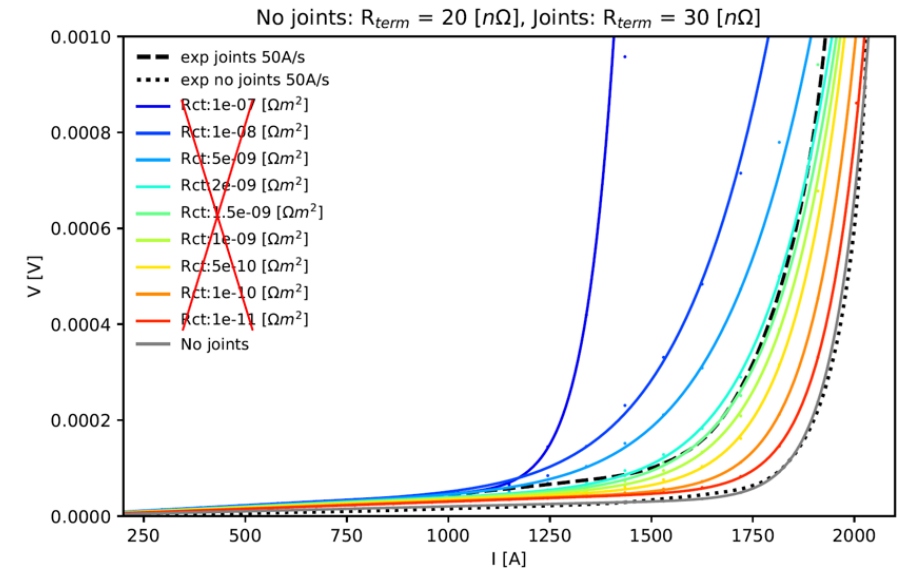
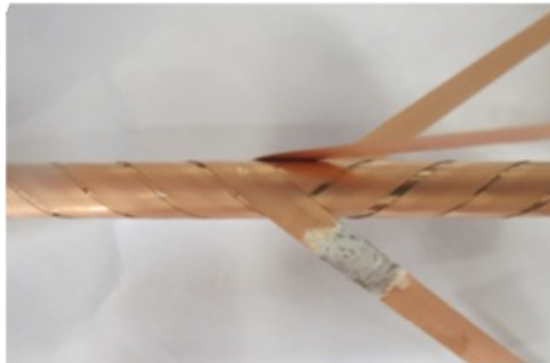
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<https://doi.org/10.1088/1361-6668/ac86fd>

Numerical investigation of current distributions around defects in high temperature superconducting CORC® cables

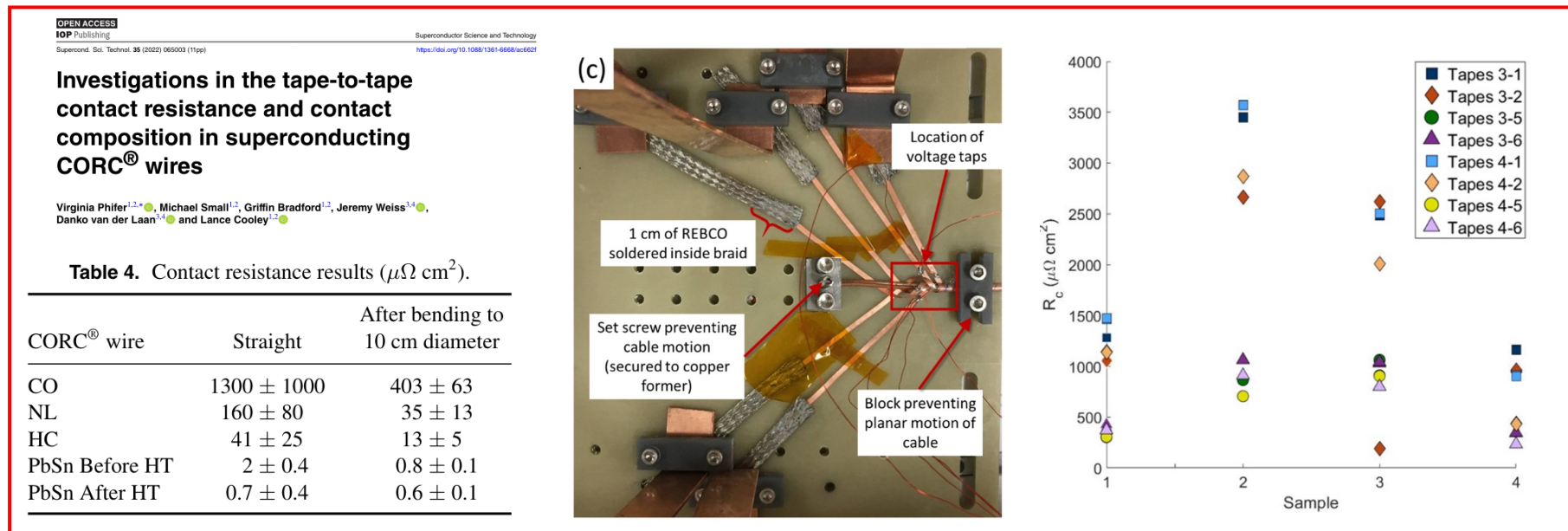
Reed Teyber^{1,*}, Maxim Marchevsky¹, Aurora Cecilia Araujo Martinez¹, Soren Prestemon¹, Jeremy Weiss^{2,3} and Danko van der Laan^{2,3}

ACT - Tape-to-tape joint / “dropout”



TITO – Tape In Tape Out

- Moved to more “direct method” of extracting contact resistivity
 - Recreating work by Virginia Phifer and Lance Cooley
 - See similar measurements by Twente
 - Measure voltage between individual tapes - $R_{CT} [\Omega m^2] \sim \frac{\Delta V A_{overlap}}{I}$



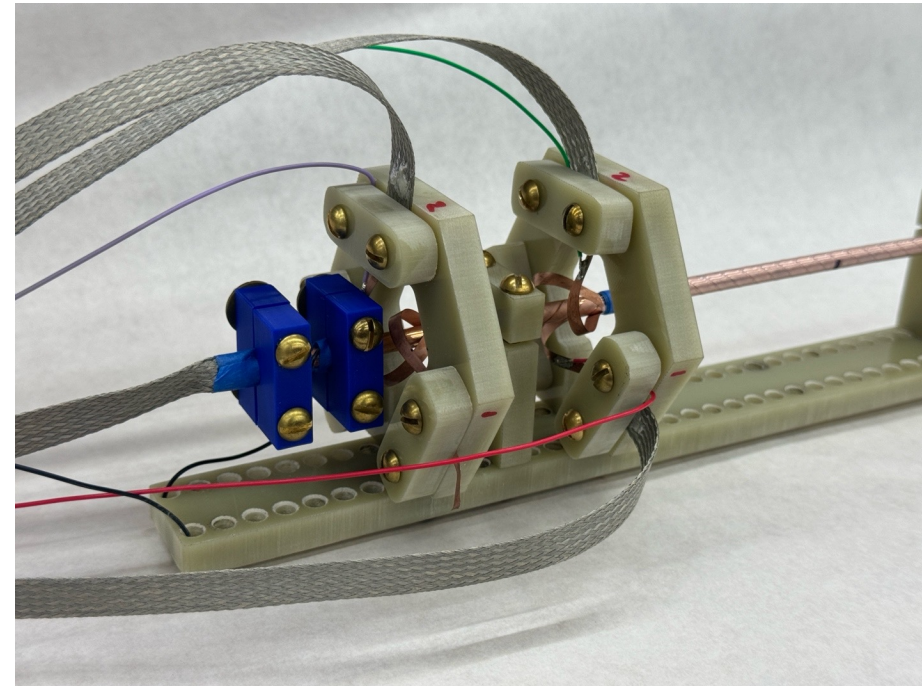
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Supercond. Sci. Technol. 33 (2020) 085009 (14pp)
<https://doi.org/10.1088/1361-6668/ab277f>

AC loss and contact resistance in REBCO CORC®, Roebel, and stacked tape cables

K Yagotintsev¹, V A Anvar^{1,2,6}, P Gao¹, M J Dhalle¹, T J Haugan¹, D C Van Der Laan¹, J D Weiss¹, M S A Hossain^{2,5} and A Nijhuis¹

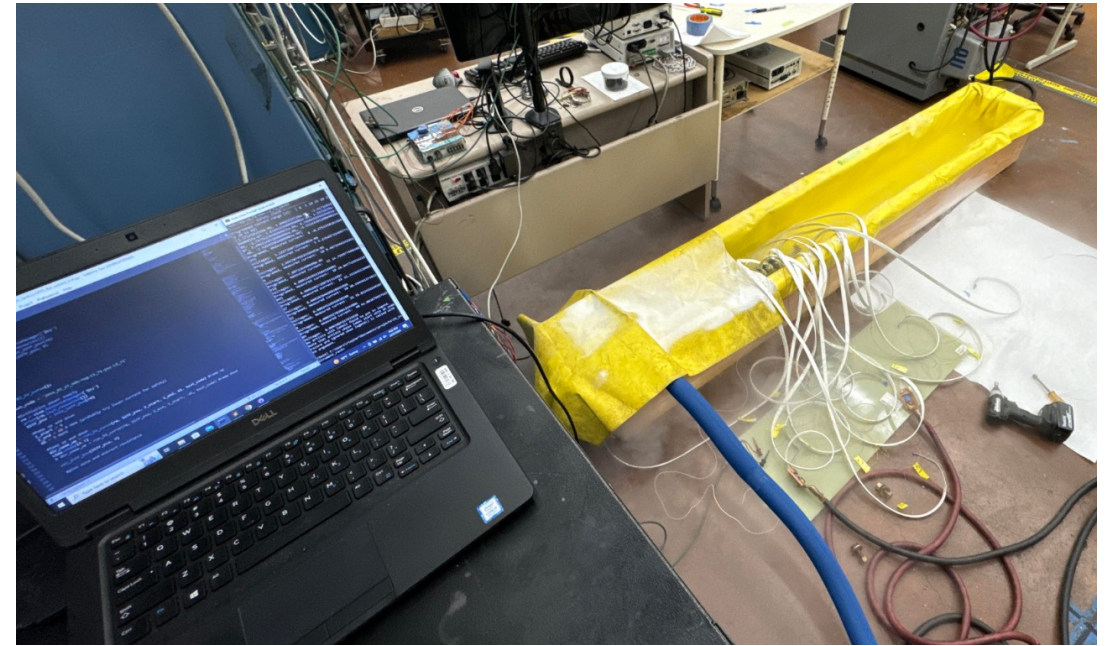
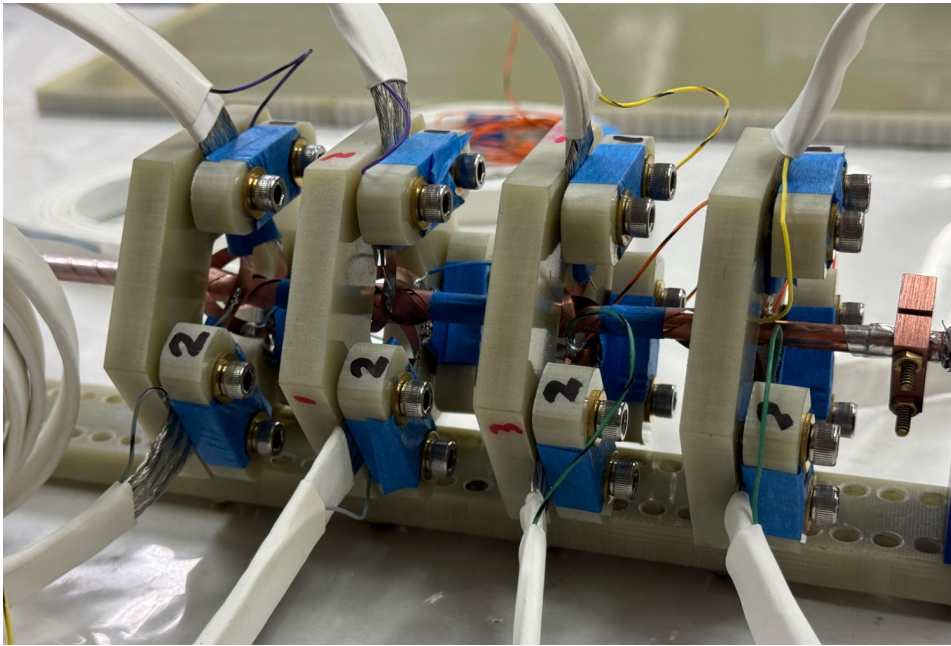
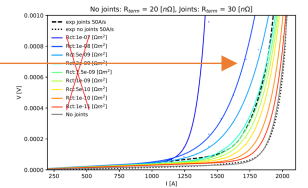
Terminations for Individual Powering

- Designed and fabricated a fixture for individual tape powering
 - Practiced full procedure on 6-tape CPRD CORC cable
 - Thanks CPRD + Ian + Lance!



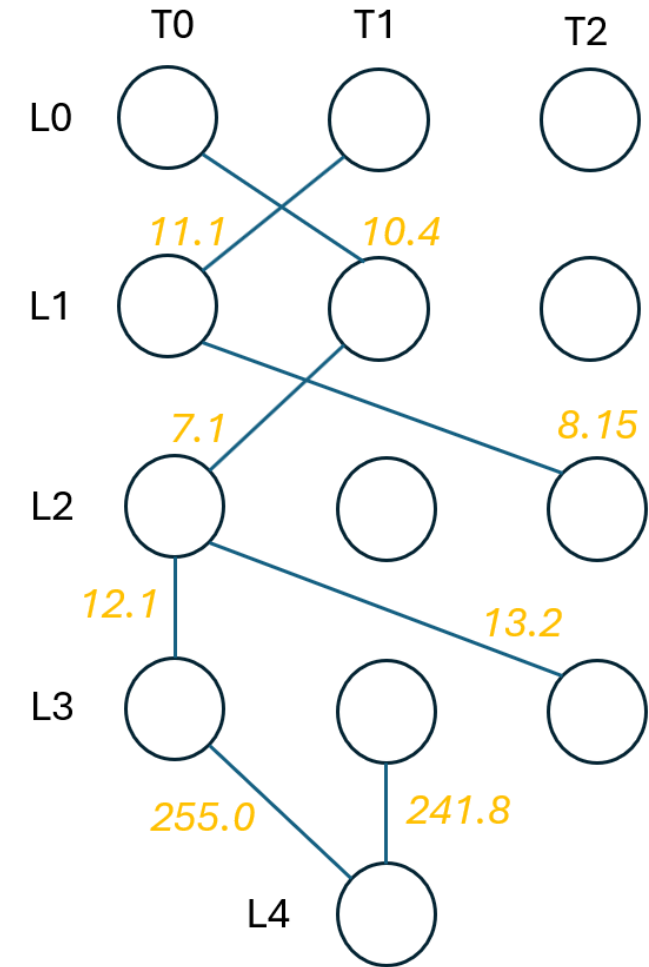
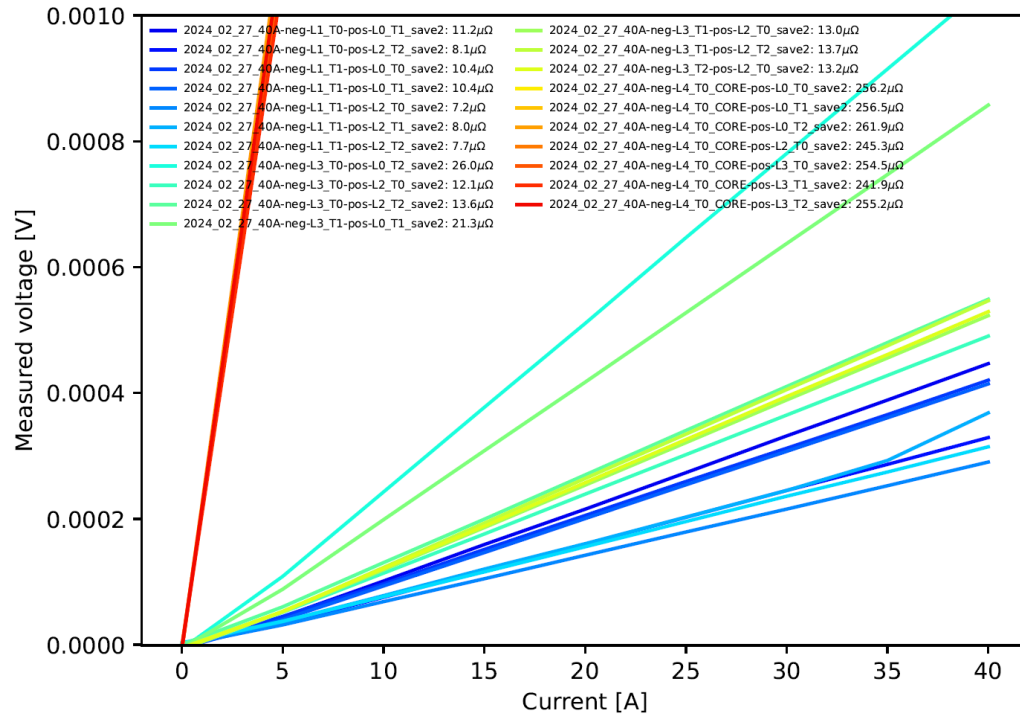
TITO experiments

- Used ACT no-defect control cable for TITO measurements
 - ~1 m, 12 tape, current injection / extraction on same side
 - Manually swapped leads and taps, powered 0->40 A: Need to automate!



TITO Measurements

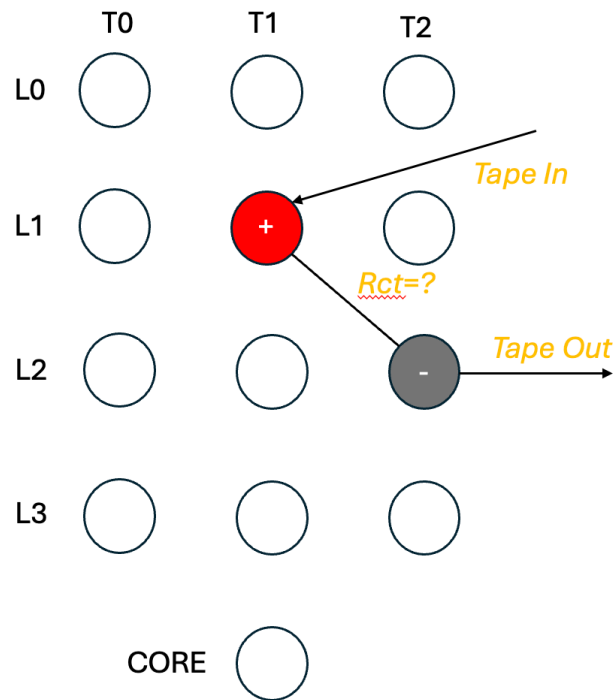
- Yellow text is measurement $R = \frac{V_{in} - V_{out}}{I_{psu}}$ [$\mu\Omega$]
- Lower Resistance on layers with more neighbors



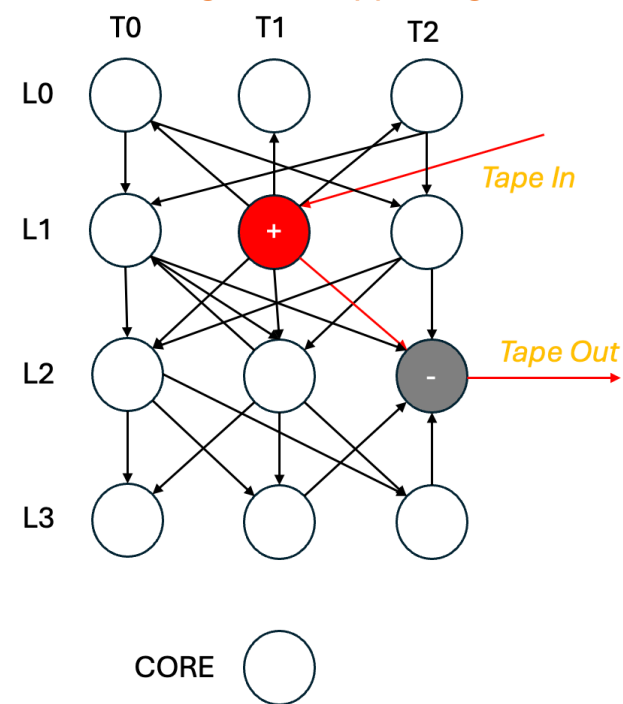
Percolation of Current

- Previous figure suggests current percolation effects need to be considered in these experiments

What calculations typically consider

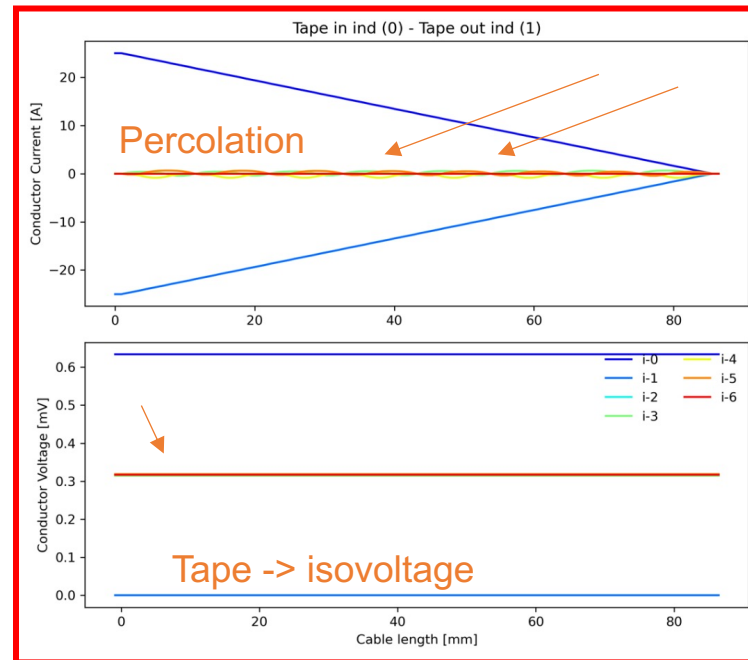
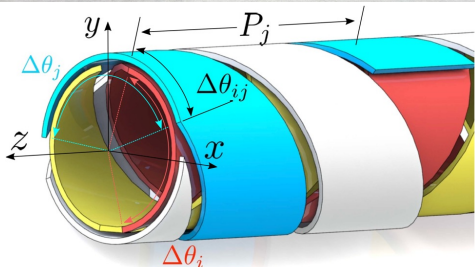
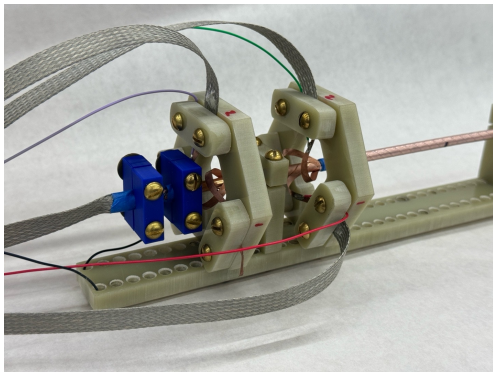


What might be happening

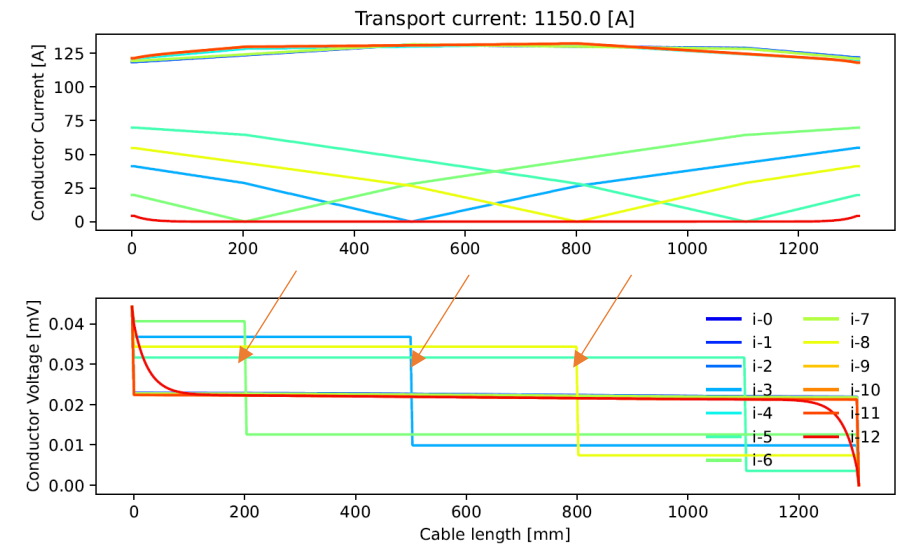


Modeling TITO Experiments

- Network model setup for short CPRD TITO experiment
- Both TITO experiments and CORC cables with (intentional!) dropouts seem almost entirely governed by linear resistive current sharing and terminations
 - Can we neglect superconductivity in modeling these (niche) superconducting cables?



Prior network model simulation w/ 4 dropouts
 ~ constant tape voltage between defects / joints!

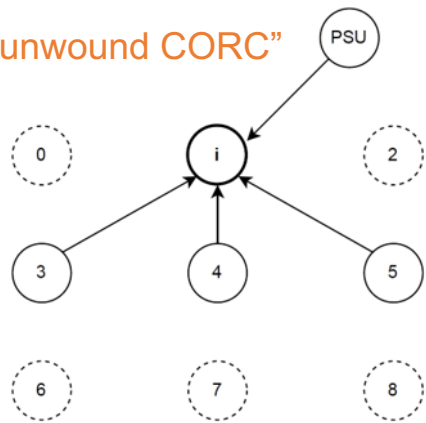


Percolation Model

- Prior model of 100mm cable motivated additional modeling
- What is the single tape voltage that balances current?
 - Write expression for current sharing to 3 tapes above, 3 tapes below
 - Repeat to build 12x12 matrix system $[1/R][V] = [I_{psu}]$
- Finite-difference Newton-Rhapson of this solution to find $R_{ct} [\Omega m^2]$
 - x is contact resistivity, $f(x) = V_{sim} - V_{exp}$

Percolation model $Ax=b$

“unwound CORC”



$$0 = \sum_{j=0}^8 \frac{V_j - V_i}{R_{i-j}} + I_{i,psu}$$

Contact resistivity & total area between tapes

$$-I_{i,psu} = -V_i \left(\frac{1}{R_{0i}} + \frac{1}{R_{1i}} + \frac{1}{R_{2i}} \right) + \frac{V_0}{R_{0i}} + \frac{V_1}{R_{1i}} + \frac{V_2}{R_{2i}}$$

Voltage of tape i as function of voltage of neighboring tape voltages

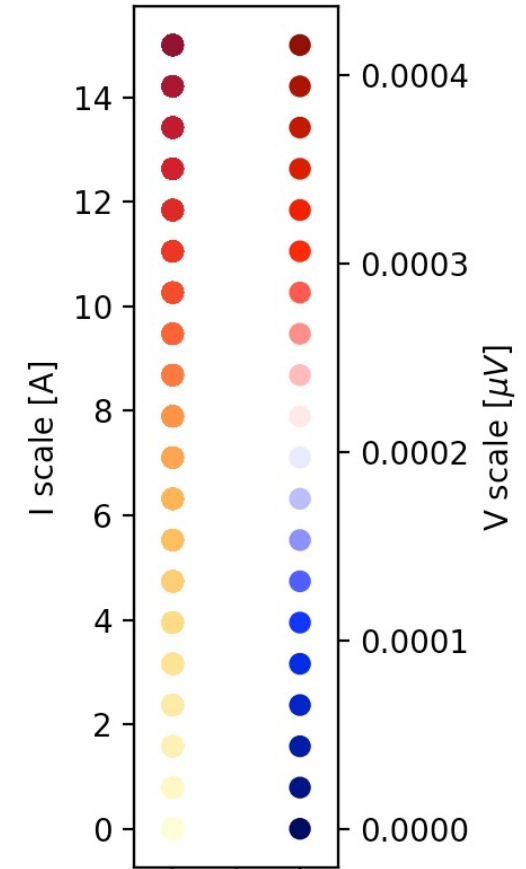
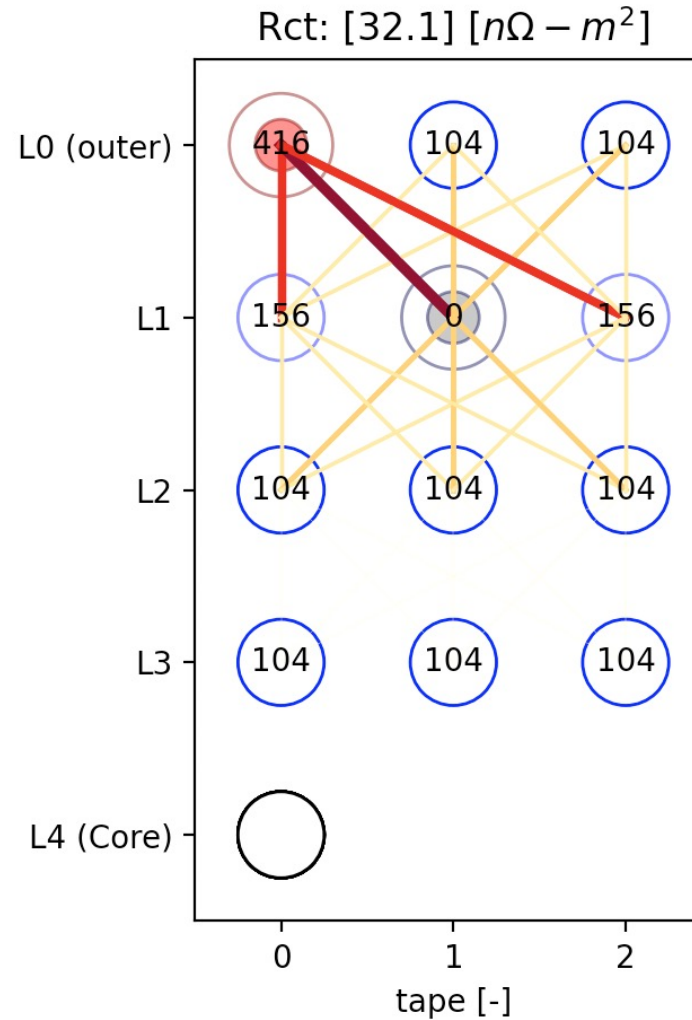
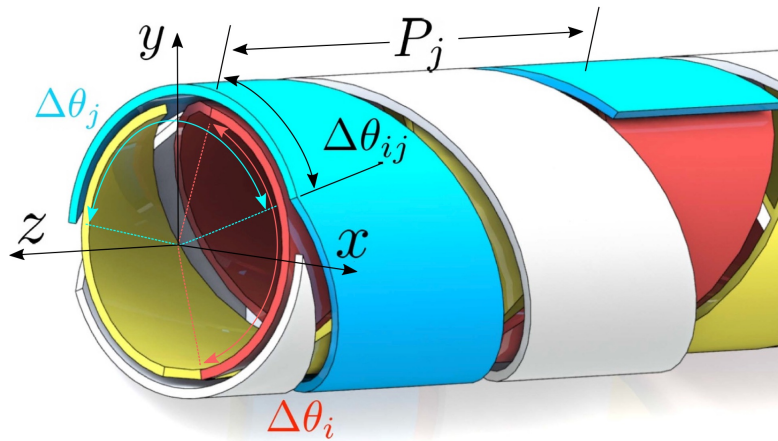
Iterative solver of $Ax=b$ to extract R_{ct}

$$x_1 = x_0 - \frac{f(x_0)}{f'(x_0)}$$

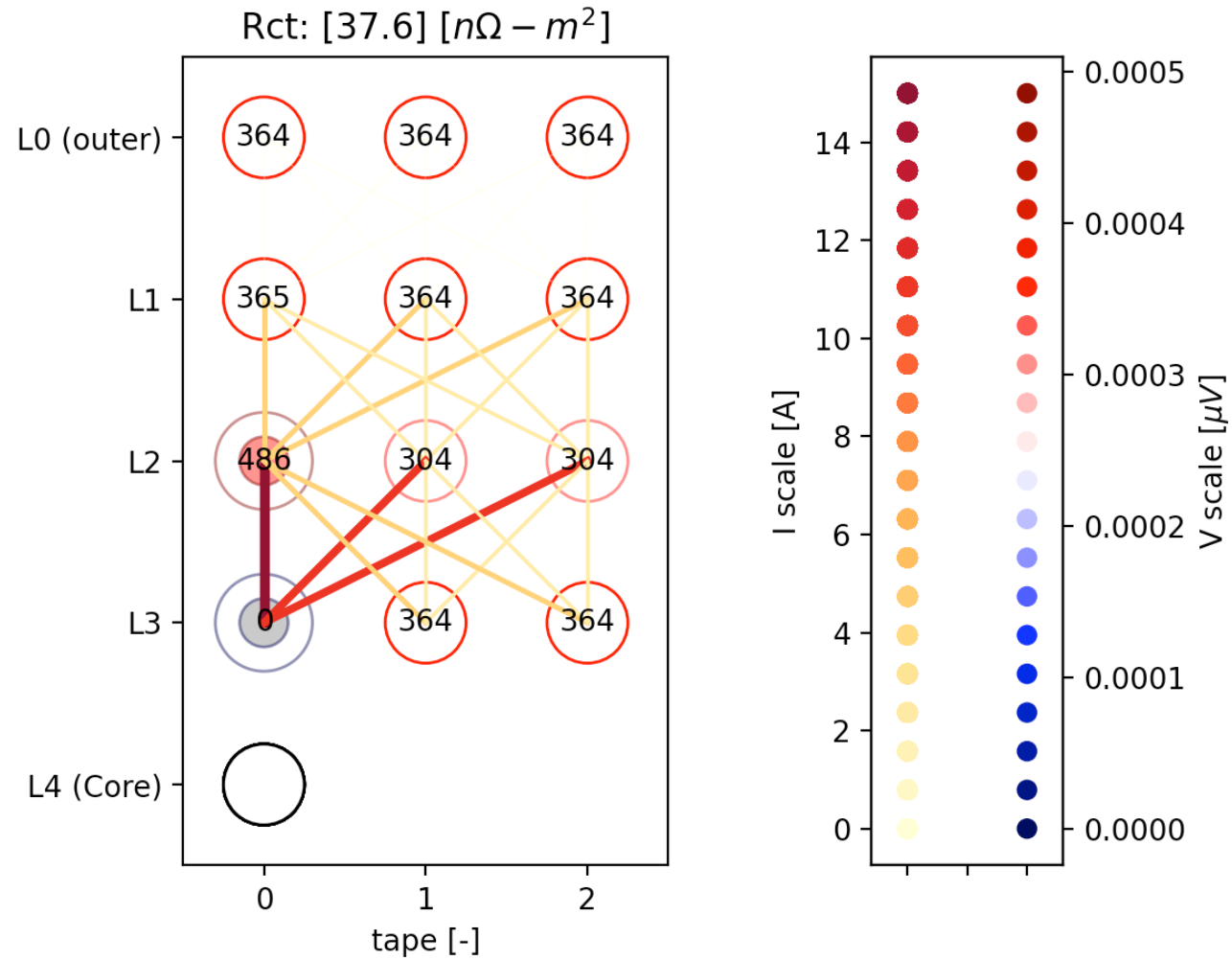
$$x_1 = x_0 - \frac{\Delta x * f(x_0)}{f(x_0 + \Delta x) - f(x_0)}$$

TITO Results

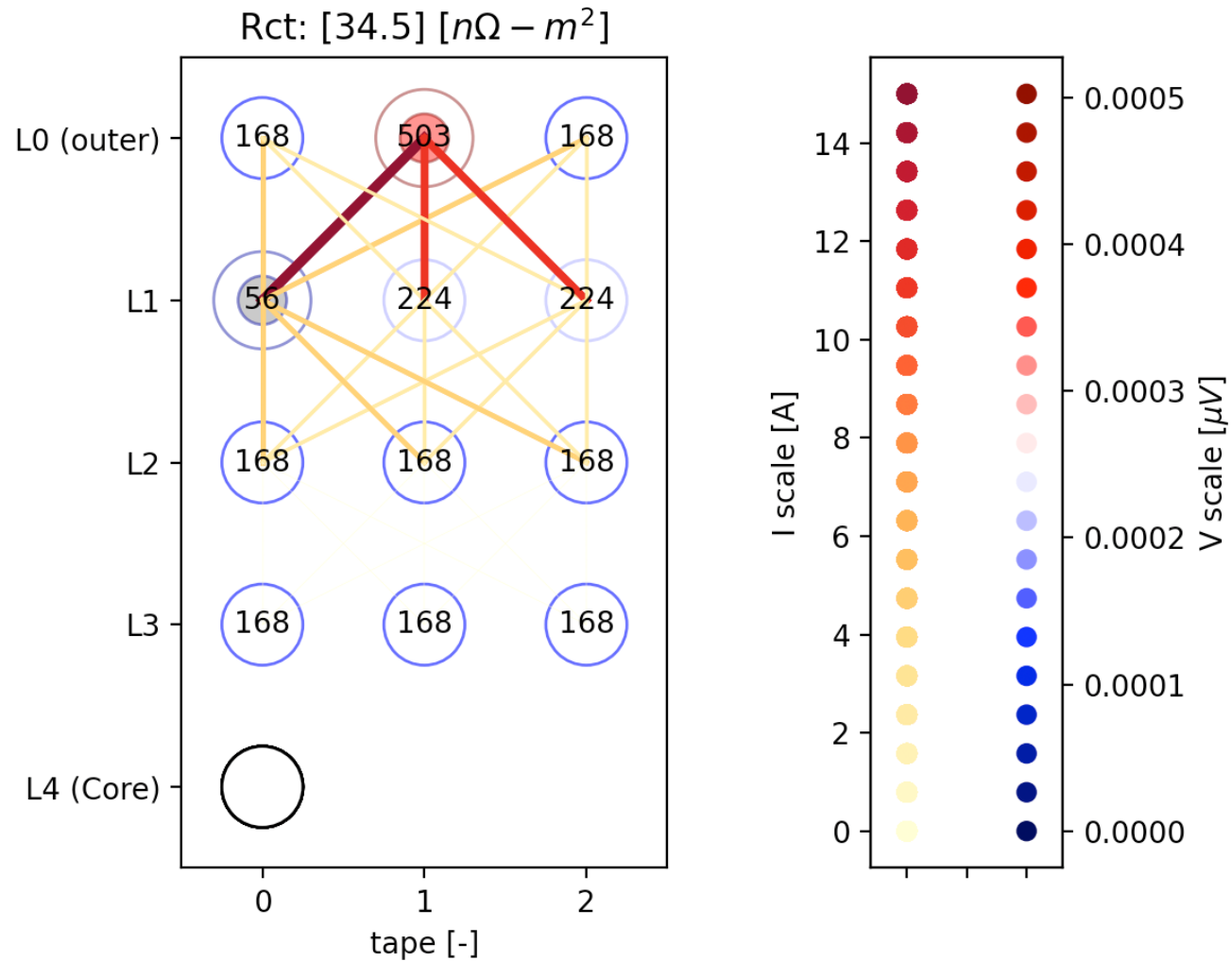
- Circles are individual tapes
- Line width, line color shows current between given tapes
- Circle color shows tape voltage (microvolts)
- Solid red, gray are in, out tapes



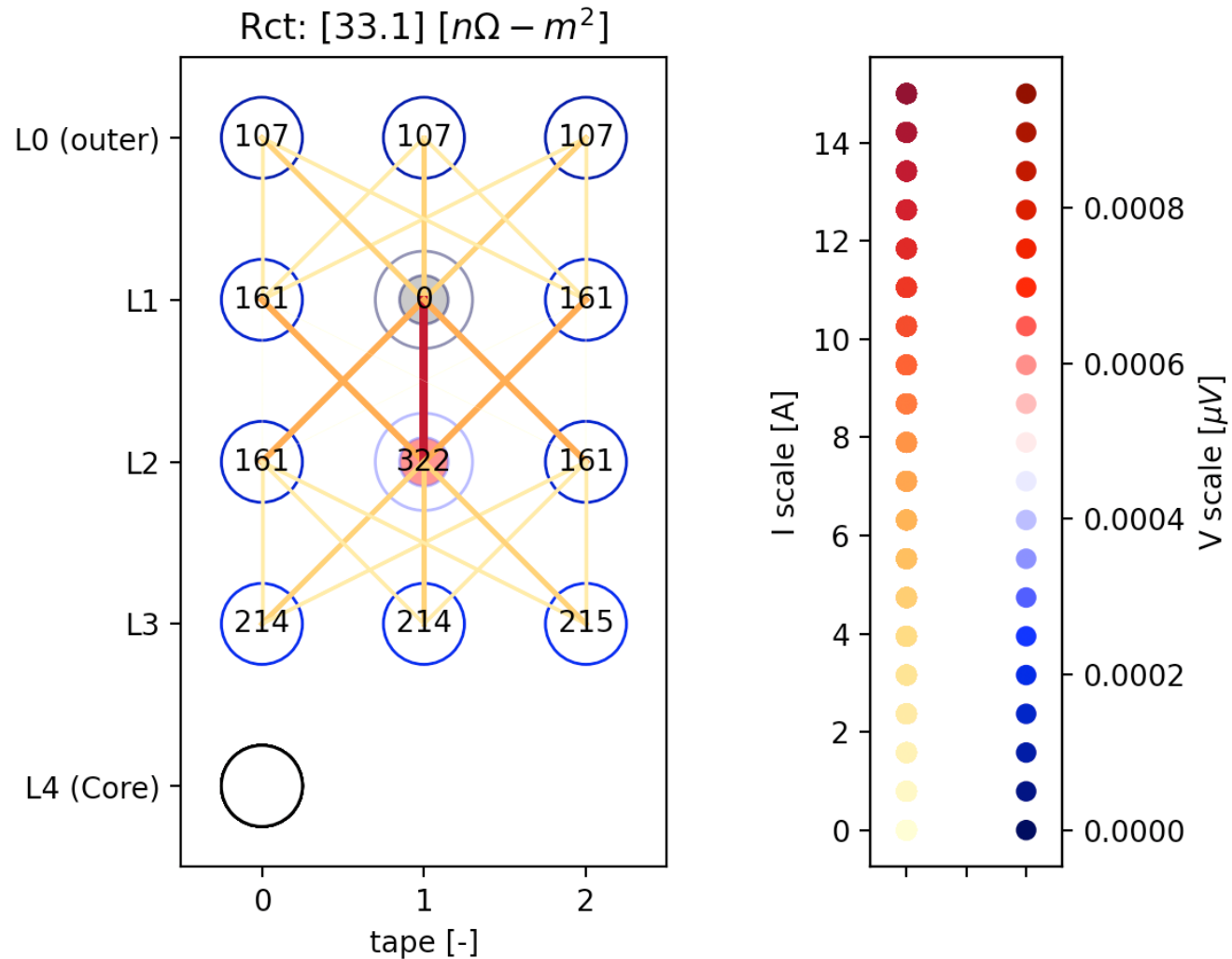
TITO Results



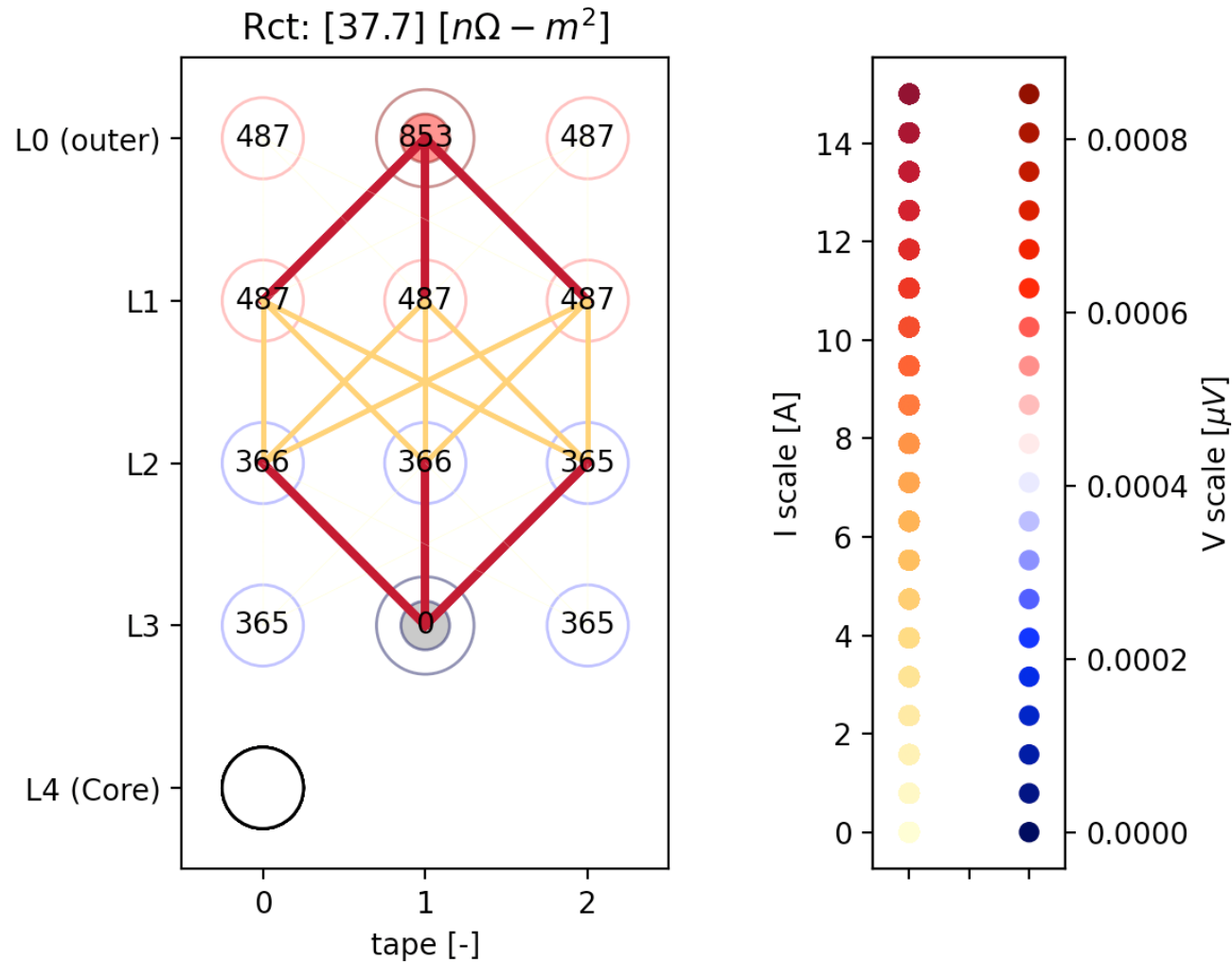
TITO Results



TITO Results

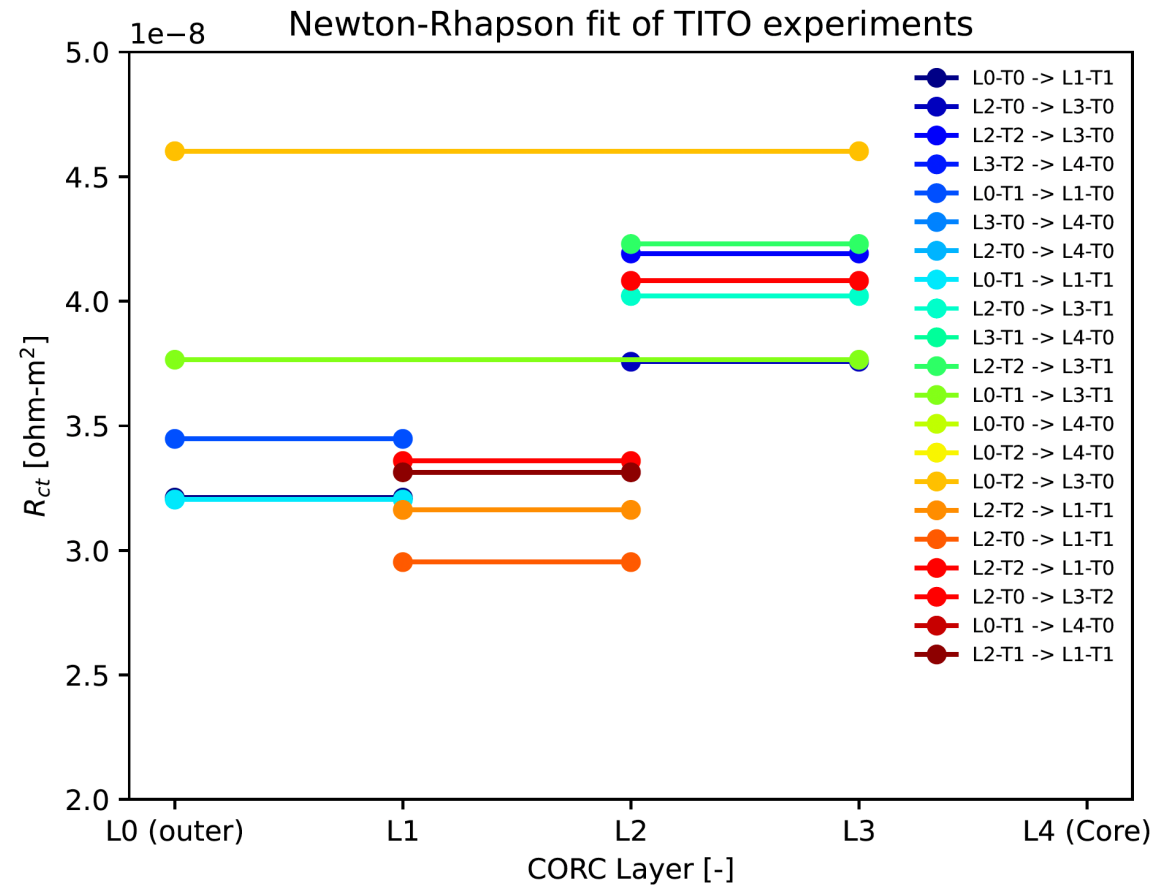
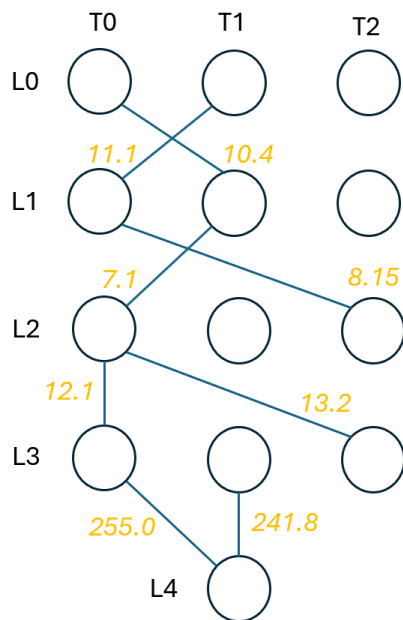


TITO Results



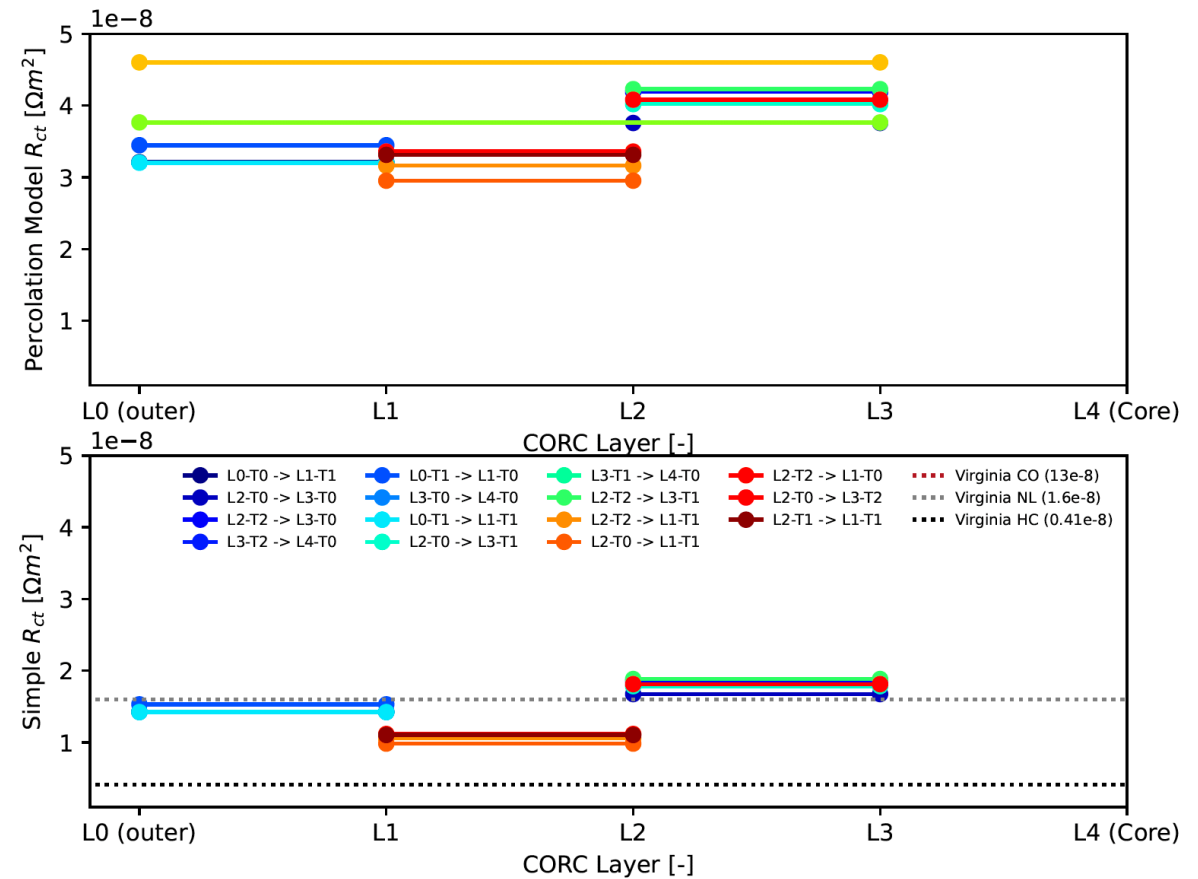
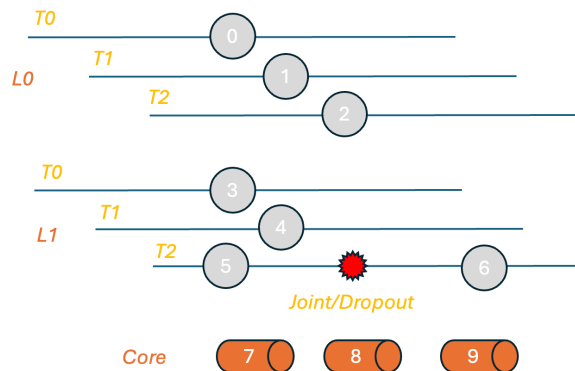
Layer Dependent Resistivity

- Appears that layer-dependent contact resistivity can now be resolved in-situ
 - Results from single cable suggest higher contact resistivity in inner layers



The impact of percolation

- Results suggest importance of considering percolation effects for in-situ contact resistivity measurements in HTS cables
 - Factor of 3 difference here, drives heating in cables with defects
- This concept serves as the basis for a possible new, fast way to model CORC cables with defects (hopefully get phase 2)



Disclaimer

- Very thankful for all the prior work done to date in this area (Virginia + Lance, Twente,...)
 - This effort was initiated out of respect for their work, after I did not succeed in extracting resistivity from network model fit to two cable I-V curves
 - Non-percolation approach great for relative comparison of different cable winding approaches, which is most useful
 - *E.g. impact of different lubricants, solder-coated, bending effects – et cetera*
 - I should be careful here as well as I need to spend more time developing percolation model and testing more cables!

Summary

- Work by ACT in Phase 1 shows encouraging results for being able to build and operate CORC cables consisting of full, intentional defects (not discussed today)
- Tape-in-tape-out experiments reveal a lot of interesting information about the cable under test, many possibilities as cable quality control / magnet post mortem
- Numerical method developed to account for current percolation in TITO experiments, extracting contact resistivity in-situ for any layer under test (think – diagnostic for real time measurement as cable is bent)
- Contact resistivity consistent with previous cables, however current percolation considerations suggest significantly higher values (i.e. internal heating) than previously shown
- The approach for considering percolation in TITO experiments is promising as the kernel for a new, fast modeling approach for CORC cables driven by defects / dropouts / joints which will be explored (hope to get phase 2)
- Thanks to ACT for including me in their research – they did the “heavy lifting” here

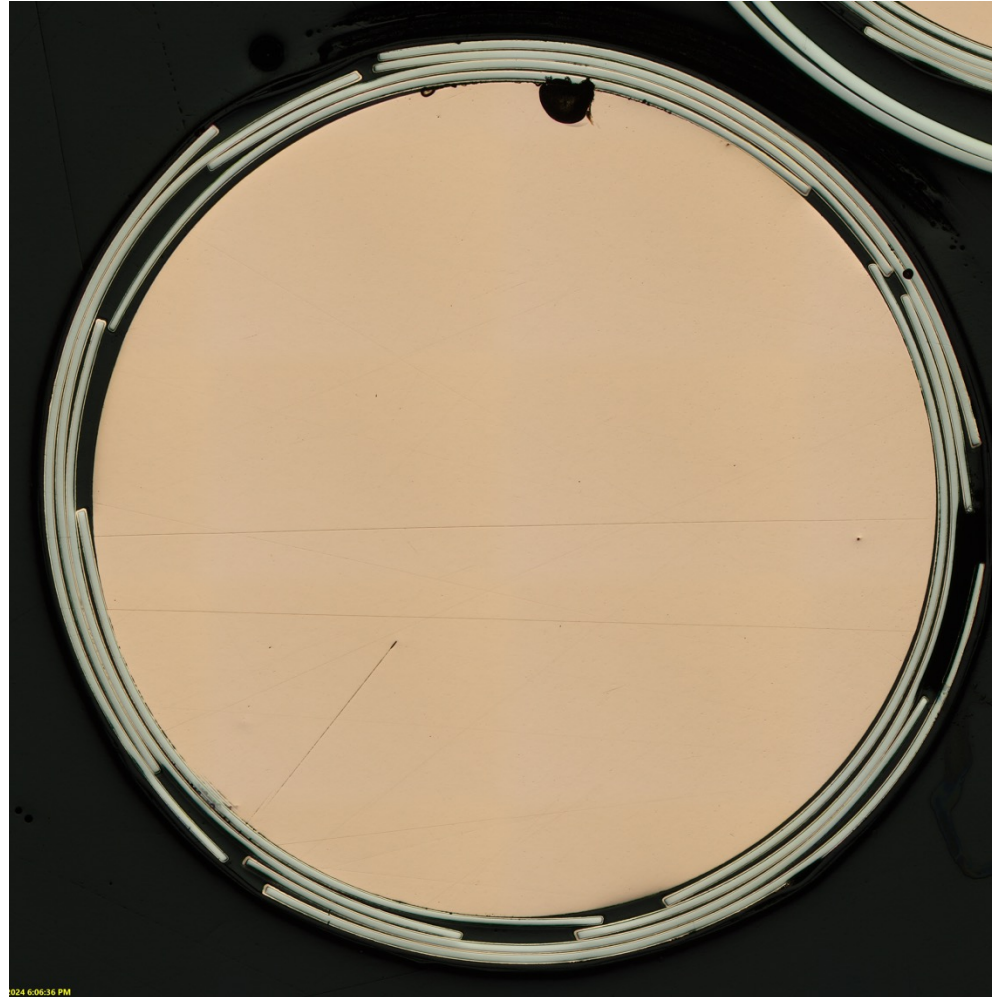
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In
progress *Nov-23* *R. Teyber*

In
progress *Mar-24* *R. Teyber*

Thanks



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